## Notice of References Cited Application/Control No. 09/839,794 Examiner Sargon N. Nano Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,006,259	12-1999	Adelman et al.	709/223
	В	US-6,779,017	08-2004	Lamberton et al.	709/203
	С	US-6,901,445	05-2005	McCanne et al.	709/225
	D	US-6,779,039	08-2004	Bommareddy et al.	709/238
	Е	US-6,895,433	05-2005	Slater et al.	709/220
	F	US-6,801,949	10-2004	Bruck et al.	709/232
	G	US-			
	Н	US-			
	_	US-			·
	7	US			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification			
	N								
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	Р								
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	S								
	Т								

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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	x		

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